## MATERIALS RESEARCH SOCIETY SYMPOSIUM PROCEEDINGS VOLUME 1713

# In-Situ Characterization of Material Synthesis and Properties at the Nanoscale with TEM

April 21-25, 2014 San Francisco, California, USA

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Curran Associates, Inc. 57 Morehouse Lane Red Hook, NY 12571 www.proceedings.com

ISBN: 978-1-5108-0569-9

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Cambridge University Press Cambridge, New York, Melbourne, Madrid, Cape Town, Singapore, São Paulo, Delhi, Tokyo, Mexico City

Cambridge University Press 32 Avenue of the Americas, New York, NY 10013-2473, USA www.cambridge.org

Materials Research Society 506 Keystone Drive, Warrendale, PA 15086 www.mrs.org

CODEN: MRSPDH

ISBN: 978-1-5108-0569-9

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